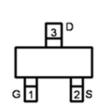
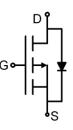


### Main Product Characteristics:

V <sub>DSS</sub>	-20V				
R <sub>DS</sub> (on)	33mΩ(typ.)				
I <sub>D</sub>	-3.5A				







SOT-23

Pin Assignments

Schematic Diagram

### **Features and Benefits**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

### **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V_GS @ 10V(1)	-3.5	Α
I <sub>DM</sub>	Pulsed Drain Current②	-14	A
$P_{D} @T_{C} = 25^{\circ}C$	Power Dissipation ③	1.25	W
V <sub>DS</sub>	Drain-Source Voltage	-20	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 12	V
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>0JA</sub>	Junction-to-Ambient		100	°C/W

## Electrical Characterizes @TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	-20	_	—	V	$V_{GS} = 0V, I_D = -250 \mu A$	
D	Static Drain-to-Source on-resistance	—	33	40	mΩ	$V_{GS}$ =-4.5V,I <sub>D</sub> =-5.0A	
$R_{DS(on)}$		_	45	53	mΩ	V <sub>GS</sub> =-2.5V,I <sub>D</sub> =-3.0A	
$V_{GS(th)}$	Gate threshold voltage	-0.5	—	-1.0	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$	
I <sub>DSS</sub>	Drain-to-Source leakage current	—	—	-1	μA	$V_{DS} = -20V, V_{GS} = 0V$	
1	Cata to Source forward lookage	—	—	100		V <sub>GS</sub> =12V	
I <sub>GSS</sub>	Gate-to-Source forward leakage		—	-100	nA	V <sub>GS</sub> = -12V	
Qg	Total gate charge	_	12	—		I <sub>D</sub> =-3.5A,	
$Q_{gs}$	Gate-to-Source charge	—	1.3	—	nC	V <sub>DS</sub> =-8V,	
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	2.5	—		$V_{GS} = -4.5V$	
t <sub>d(on)</sub>	Turn-on delay time	—	8.5	—		$V_{GS}$ =-10V, $V_{DD}$ =-10V, $R_{GEN}$ =3 $\Omega$ $I_D$ = -0.5A	
t <sub>r</sub>	Rise time	_	10	—			
$t_{d(off)}$	Turn-Off delay time	—	39	—	ns		
t <sub>f</sub>	Fall time		14	—		$I_{\rm D} = -0.5 {\rm A}$	
C <sub>iss</sub>	Input capacitance		889	—		$V_{GS} = 0V$	
Coss	Output capacitance		102	_	pF	V <sub>DS</sub> = -15V	
C <sub>rss</sub>	Reverse transfer capacitance	_	94	—		f = 1MHz	

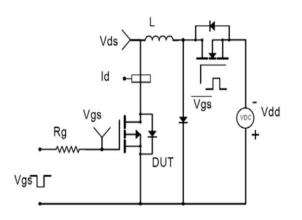
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current (Body Diode)	_	_	-3.5	А	MOSFET symbol showing the G→ H ↓	
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	_	_	-14	А	integral reverse	
V <sub>SD</sub>	Diode Forward Voltage		-0.8	-1.3	V	I <sub>S</sub> =-1.3A, V <sub>GS</sub> =0V	

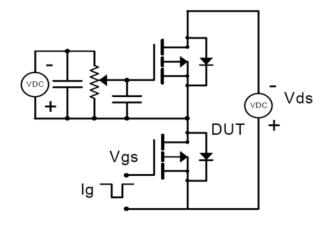


## **Test Circuits and Waveforms**

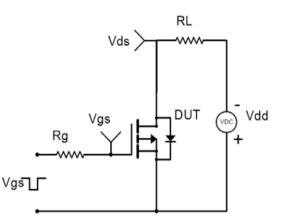
#### EAS Test Circuit:



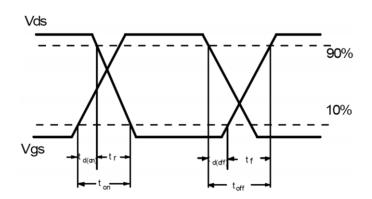
Gate Charge Test Circuit:



#### Switching Time Test Circuit:





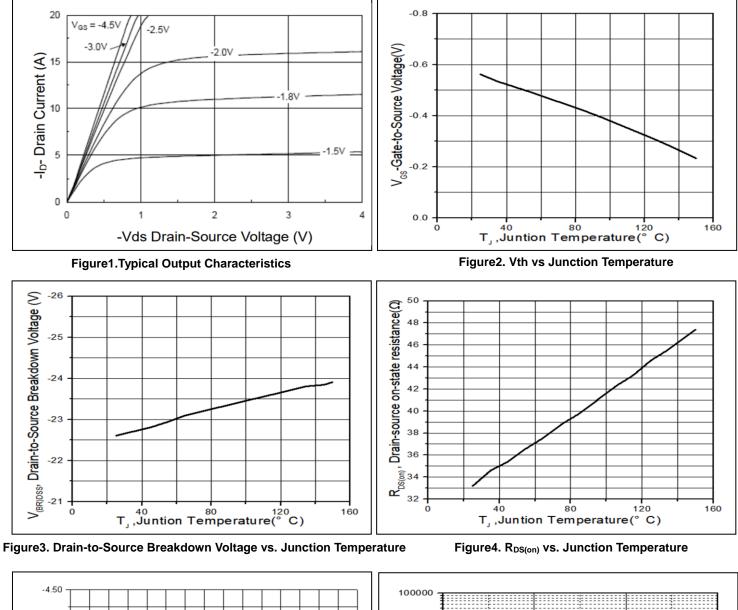


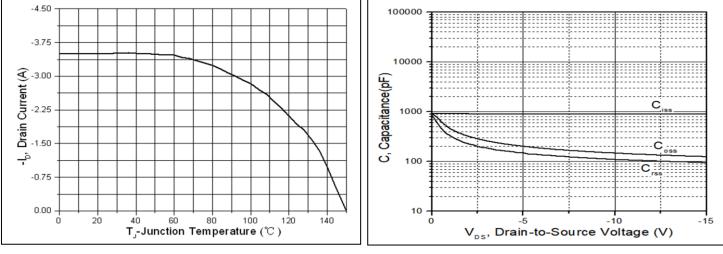
### Notes:

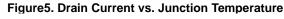
- ①Calculated continuous current based on maximum allowable junction temperature.
- 2 Repetitive rating; pulse width limited by max. junction temperature.
- $\ensuremath{\textcircled{3}}$  The power dissipation P<sub>D</sub> is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25$ °C



## **Typical Electrical and Thermal Characteristics**

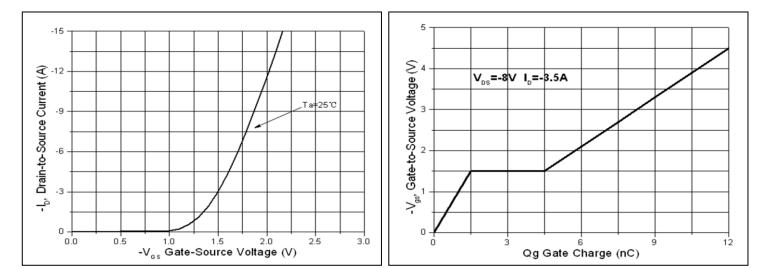












## **Typical Electrical and Thermal Characteristics**



Figure8. Gate source voltage vs. Gate Charge

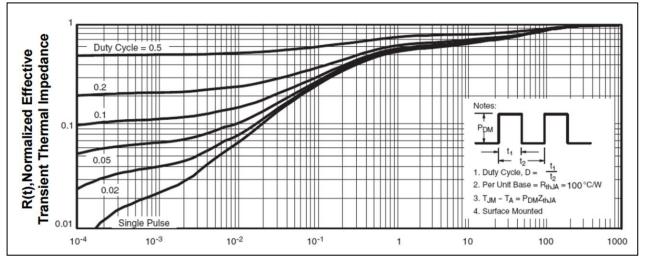
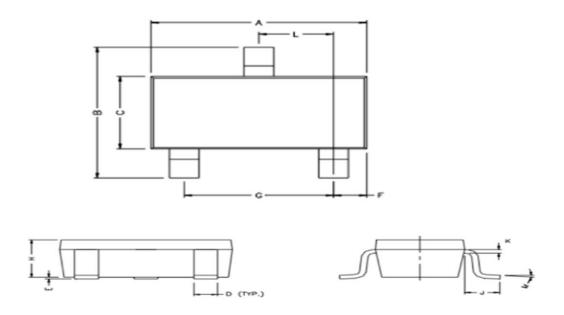


Figure9. Normalized Maximum Transient Thermal Impedance



### **Mechanical Data:**

SOT-23 Package Outline(Unit:mm)



REF.	Millimeter		REF.	Millimete		
KEF.	Min.	Max.	KEF.	Min.	Max.	
Α	2.80	3.00	G	1.80	2.00	
В	2.30	2.50	Н	0.90	1.1	
С	1.20	1.40	K	0.10	0.20	
D	0.30	0.50	J	0.35	0.70	
E	0	0.10	L	0.92	0.98	
F	0.45	0.55	М	0°	10°	



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